

May 2009

# **FDMS8880**

# N-Channel PowerTrench $^{\rm I\!R}$ MOSFET 30 V, 21 A, 8.5 m $\Omega$

### **Features**

- Max  $r_{DS(on)}$  = 8.5 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 13.5 A
- Max  $r_{DS(on)}$  = 13.0 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 10.9 A
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- MSL1 robust package design
- RoHS Compliant

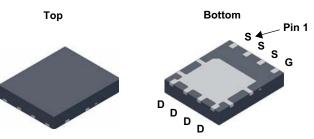


### **General Description**

The FDMS8880 has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{\text{DS}(on)}$  while maintaining excellent switching performance.

### **Applications**

- Synchronous Buck for Notebook Vcore and Server
- Notebook Battery Pack
- Load Switch



Power 56

# D 5 4 G D 6 3 S D 7 2 S D 8 1 S

### MOSFET Maximum Ratings TA = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			30	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		21	
I <sub>D</sub>	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		51	1
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	13.5	A
	-Pulsed			80	1
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	60	mJ
В	Power Dissipation	T <sub>C</sub> = 25 °C		42	w
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	] vv
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

### **Thermal Characteristics**

$R_{ heta JC}$	Thermal Resistance, Junction to Case	3.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	5/44

### **Package Marking and Ordering Information**

Device Marking	Device	Device Package Reel Size		Tape Width	Quantity	
FDMS8880	FDMS8880	Power 56	13 "	12 mm	3000 units	

### Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		19		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA

### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.2	1.9	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		-7		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 13.5 A		6.3	8.5	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 10.9 \text{ A}$		9.0	13.0	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 13.5 \text{ A}, T_J = 125 ^{\circ}\text{C}$		9.6	13.0	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 13.5 A		78		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V -45 V V -0 V	1195	1585	pF
Coss	Output Capacitance	√V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, √f = 1 MHz	234	315	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	-1 - 1 1011 12	161	245	pF
$R_q$	Gate Resistance		0.9	1.8	Ω

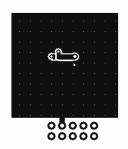
### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				9	18	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 13	.5 A,		6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10 V, R <sub>GEN</sub> =	$V_{DD}$ = 15 V, $I_{D}$ = 13.5 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		23	27	ns
t <sub>f</sub>	Fall Time				4	10	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V			23	33	nC
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 5 V	V <sub>DD</sub> = 15 V,		13	18	nC
$Q_{gs}$	Gate to Source Charge		I <sub>D</sub> = 13.5 A		3.5		nC
Q <sub>qd</sub>	Gate to Drain "Miller" Charge				5.1		nC

### **Drain-Source Diode Characteristics**

V	Vob ISource to Drain Diode Forward Voltage F	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)	0.74	1.2	V
VSD		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 13.5 A (Note 2)	0.84	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I⊑ = 13.5 A. di/dt = 100 A/us	20	32	ns
Q <sub>rr</sub>	Reverse Recovery Charge	iF = 13.3 A, αι/αι = 100 A/μs	8	16	nC

1. R<sub>0,JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,JC</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%. 3.Starting T $_J$  = 25  $^{\circ}C,$  L = 0.3 mH, I $_{AS}$  = 19 A, V $_{DD}$  = 27 V, V $_{GS}$  = 10 V.

### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

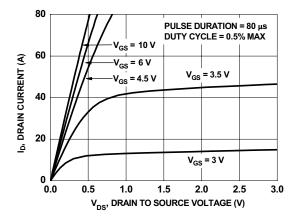


Figure 1. On Region Characteristics

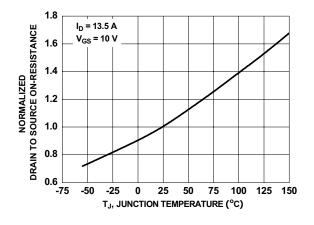


Figure 3. Normalized On Resistance vs Junction Temperature

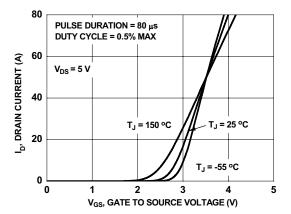


Figure 5. Transfer Characteristics

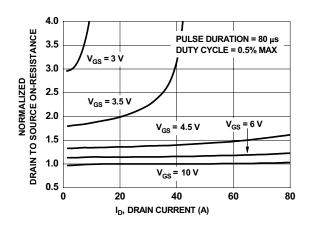


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

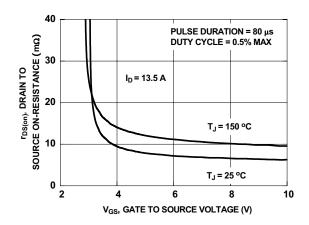


Figure 4. On-Resistance vs Gate to Source Voltage

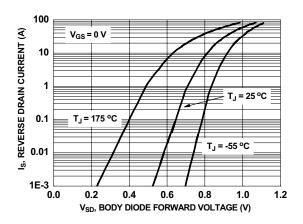


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

### **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

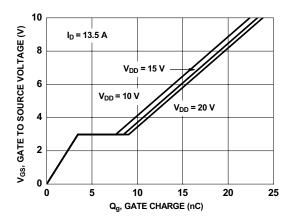


Figure 7. Gate Charge Characteristics

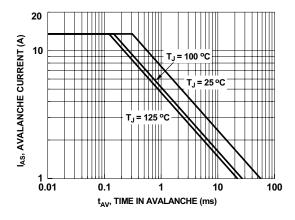


Figure 9. Unclamped Inductive Switching Capability

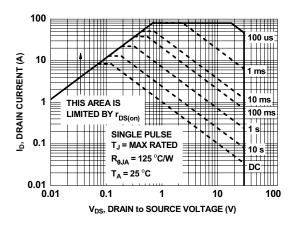


Figure 11. Forward Bias Safe Operating Area

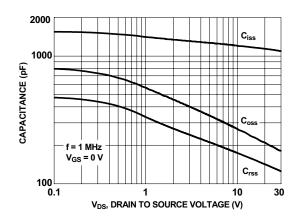


Figure 8. Capacitance vs Drain to Source Voltage

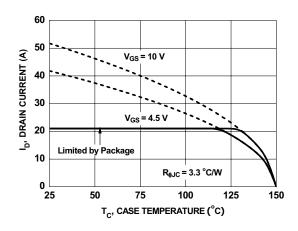


Figure 10. Maximum Continuous Drain Current vs Case Temperature

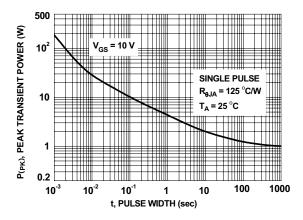


Figure 12. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

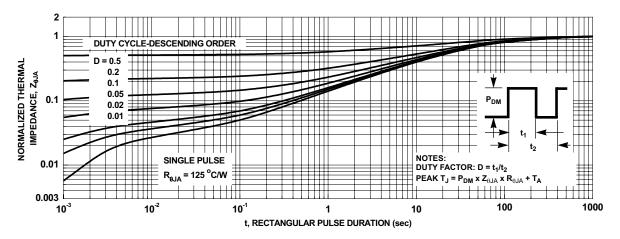
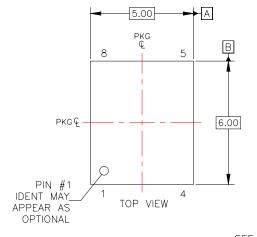
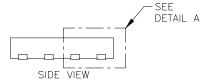
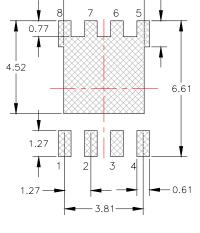


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

### **Dimensional Outline and Pad Layout**

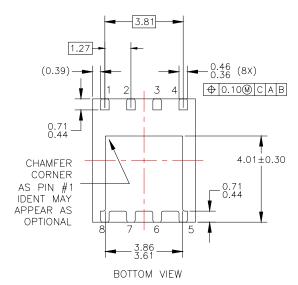


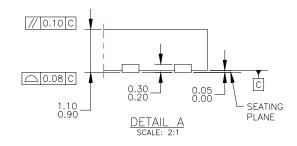


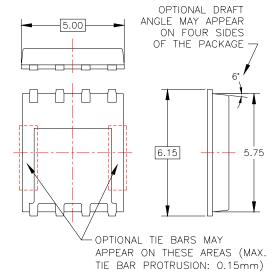


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LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE:
  JEDEC MO-240, ISSUE A, VAR. AA,
  DATED OCTOBER 2002.
  ALL DIMENSIONS ARE IN MILLIMETERS.
  DIMENSIONS DO NOT INCLUDE BURRS
- OR MOLD FLASH, MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- DRAWING FILE NAME: PQFN08AREV4





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